

Notice of References Cited	Application/Control No. ✓ 10/027,462	Applicant(s)/Patent Under Reexamination YAROSLAVSKY ET AL.	
	Examiner Manav Seth	Art Unit 2625	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,067,164	05-2000	Onoguchi et al.	356/401
*	C	US-3,918,071	11-1975	Albrecht, Fritz	396/101
*	D	US-4,404,594	09-1983	Hannan, William J.	348/355
*	E	US-4,825,065	04-1989	Imai, Ryoichi	250/205
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*	G	US-5,534,924	07-1996	Florant, Olivier	348/364
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
✓	U	Rooks et al., IEEE, June 5 1999, "Development of an inspection process for ball-grid-array technology using scanned-beam X-ray laminography". (pp. 851-861)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.